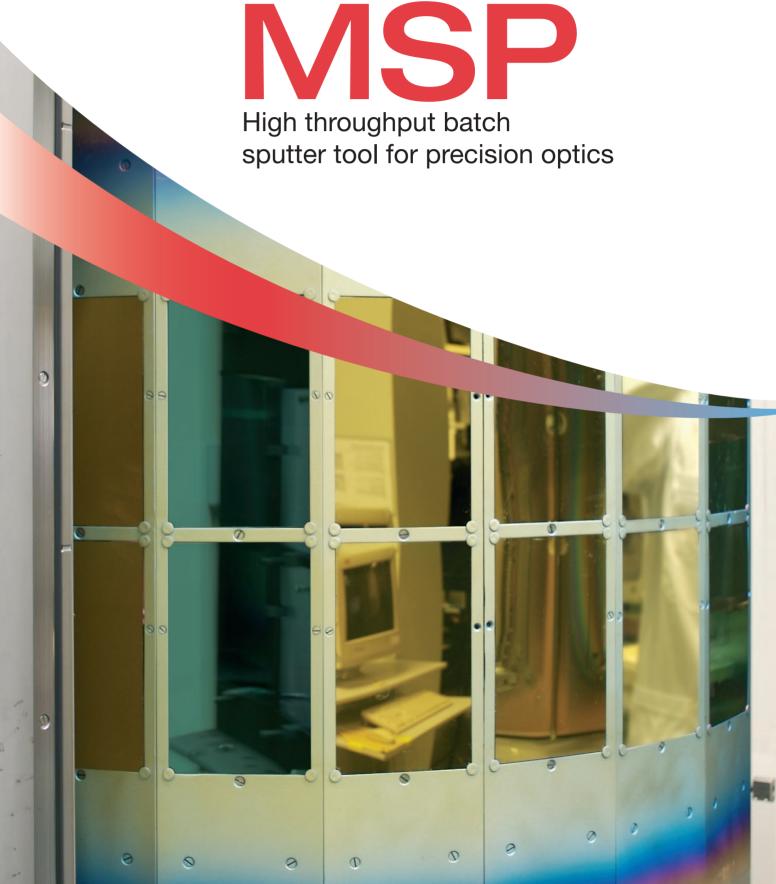


Typical Sys	Typical System Capacities				
Substrate Size	Batch Size				
180 x 136 mm	40				
180 x 110 mm	48				
8 inch diameter	up to 24				



Evatec offers complete solutions for thin film deposition and etch in the optical and semiconductor markets. Evatec engineers are able to offer practical production advice from R&D to prototyping and mass production. We recognize that no single technique offers the answer to all problems. With a technology portfolio including standard and enhanced evaporation as well as sputter, we are ready to offer sampling services and custom engineering to meet out customers individual needs.

We provide sales and service through our global network of local offices. For more information visit us at www.evatecnet.com or contact our head office.

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All machine images and colour wheel on page 2 courtesy of Oerlikon Optics. Product descriptions, photos and data are supplied within the brochure for general information only and may be superseded by any data contained within Evatec quotations, manuals or specifications.



MSP Why sputter technology for optical thin films

MSP The Evatec Advantage

Sputter technology offers the potential to deposit hard, dense, oxide films with superb environmental and temperature stabilities. Key to its successful deployment in the manufacture of precision optical thin films is the ability to achieve high precision time after time. This requires integration of the right cathode & control technology onto a robust production platform. For selected mass production applications with the most demanding optical performance, sputtering is then a powerful tool to produce coatings at the lowest unit manufacturing costs.

MSP technology

Best process repeatability

Proven in mass production

Sputter technology benefits

Superior spectral stability

Superior spectral precision

Cold processing

As home of the industry standard Balzers BAK thin film batch evaporator, Evatec designers and application engineers have the benefit of more than 50 years experience

in delivering robust production tools for thin film deposition and etch. The "MSP" Sputter tool builds on the knowledge gained in optimising coating tool architecture and system control by starting with a mechanical platform for the best production reliability. It then incorporates proprietary sputter and process control technology to achieve highly stable optical films at low temperature over large areas in a high throughput vertical batch sputter tool. Incorporating 4 process cathodes, the tool is ideal for the production of edge and bandpass filters, TCOs and antireflection coatings on glass and polymeric substrates.

With unique access to the knowledge gained in day to day production of sputtered films, Evatec offers turnkey process solutions for cost-effective mass production.

TCOs & Anti-reflection Coatings Edge & Bandpass Filters Projection Display Notch Filters Imaging TiO, Nb, O, Ta, O, SiO,

MSP 5 steps to the best



- **1.** The coating chamber is pumped by a Turbomolecular and Meissner combination for rapid processing of glass and polymeric substrates. The motor-driven chamber door is removed completely during load / unload to allow easy access to cathodes and substrate drum.
- 2. Substrates are loaded into simple segments and mounted onto a 1 metre diameter carrier drum. The same drum can be fitted with a whole range of segment designs according to the substrate size.
- 3. Four vertically mounted cathodes are optimised for large area precision coating over a 380mm long deposition zone. Proprietary magnet tuning systems ensure the highest uniformity levels can be maintained easily by operating personnel during the target life.

Cathodes are operated in DC or mid frequency AC mode depending upon process materials for;

- Direct deposition of fully oxidized optical quality films
- Low substrate temperatures for processing sensitive polymer or cemented substrates
- Deposition uniformities of better than ±1%

...and all without any internal uniformity masks!

technologies;

Closed loop plasma process monitoring and control ensures that cathode technology runs with optimum chemistry and stability in a reactive gas environment.

Broadband Optical Monitoring with direct substrate measurement is used for end point control enabling production of the most complex multilayer coatings.

4. The MSP employs two key in situ process control 5. Evatec's Khan control platform is built on a standard industrial server running under Windows XP and offers complete closed loop control of the system, deposition sources and control systems. Features include:

- Graphical User Interface with up to 4 windows

- and analyzed
- Full integration of plasma emission and optical monitoring process control systems
- · Five Operating Levels with password protection for individual users
- Automatic Process Control (Start, Stop, Hold, Abort, Retry Step, Next Step)
- Real Time and hiostorical trending (up to 25 user-selected values) can be monitored
- Process Run and Maintenance Statistic

Evatec MSP The optical quality speaks for itself...

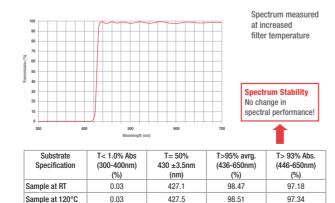
...and with the best production economics to match

- Fast processes at up to 40% of the conventional metal sputter rates
- High yields consistent with mass production

No Temperature Shift

Sample at 180°C

0.04

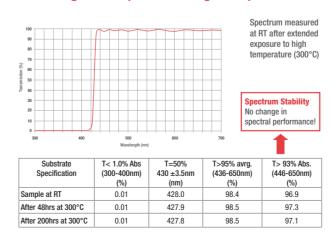


427.8

98.47

97.24

Stable against exposure to high temperature



Quality features of MSP sputtered films at a glance

High transmittance

Temperature shift<1nm from 25C to 120C

No humidity shift

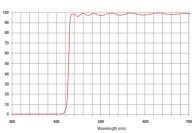
Narrow cut on / cut off tolerances better than $\pm 1\%$

Steep slope edges

Satisfying MIL specifications



Stable against exposure to high Humidity



Spectrum measured at RT after extended exposure to high humidity (MIL-C-14806A)

Spectrum Stability No change in spectral performance

				_		
Substrate Specification	T< 1.0% Abs (300-400nm)		T> 95% avg. (436-650nm)	T> 93% Abs. (446-650nm)		Slope (20% - 80%)
	(%)	(nm)	(%)	(%)	(%)	(nm)
Sample 1 at RT after coating	0.01	427.3	98.44	96.63	97.57	5.1
Sample 1 after humidity Test (MIL-C-14806A)	0.01	427.4	98.18	96.10	97.33	5.1